

(2) U.S. Application Serial No. 09/131,383, filed August 7, 1997, titled "Method and Apparatus of an Inspection System Using an Electron Beam", and

Al
Wick
(3) U.S. Application Serial No. 08/811,511, filed March 4, 1997, titled "Method and Apparatus for Inspection Integrated Circuit Pattern".

The disclosures of the above applications are hereby incorporated by reference. --

IN THE INVENTORSHIP

Please delete Maki Ito as an inventor.

REMARKS

The specification has been amended to claim priority of Serial No. 09/206,869 of which this is a divisional and related to U.S. Application Serial No. 09/258,461, filed February 26, 1999, titled "Convergent Charged Particle Beam Apparatus and Inspection Method Using Same", U.S. Application Serial No. 09/131,383, filed August 7, 1997, titled "Method and Apparatus of an Inspection System Using an Electron Beam", and; (3) U.S. Application Serial No. 08/811,511, filed March 4, 1997, titled "Method and Apparatus for Inspection Integrated Circuit Pattern".

Maki Ito, an inventor in the parent has been deleted since his invention is no longer being claimed in this application.

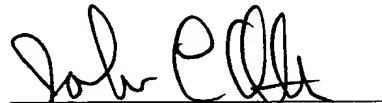
The Examiner is invited to call the undersigned at (202) 220-4200 to discuss any information concerning this application.

An Information Disclosure Statement is submitted herewith. The Information Disclosure Statement lists the references considered by the Examiner in the parent application.

The Office is hereby authorized to charge any additional fees under 37 C.F.R. § 1.16 or § 1.17 or credit any overpayment to Deposit Account No. 11-0600.

Respectfully submitted,

Dated: April 11, 2001


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